Clarifications/Corrections to the Data Sheet:

In the Device Data Sheet (DS39605F), the following clarifications and corrections should be noted. Any silicon issues related to the PIC18F1220/1320 will be reported in a separate silicon errata. Please check the Microchip web site for any existing issues.

1. Module: Enhanced Addressable Universal Synchronous Asynchronous Receiver Transmitter (EUSART)

   The note box is added after the second paragraph of Section 16.2.3 “Auto-Baud Rate Detect”, on Page 139. The two paragraphs and note appear as shown.

16.2.3 AUTO-BAUD RATE DETECT

The Enhanced USART module supports the automatic detection and calibration of baud rate. This feature is active only in Asynchronous mode and while the WUE bit is clear.

The automatic baud rate measurement sequence (Figure 16-1) begins whenever a Start bit is received and the ABDEN bit is set. The calculation is self-averaging.

   Note: Some silicon revisions use the falling edges of the Sync byte for baud rate measurement. In these devices, ABDEN may be set during the preceding Break. In other silicon revisions, the rising edges are used. In these devices, the RX input must be high (Break completed) before ABDEN is set. If this is not done, the end of the Break signal could be interpreted as the start of the Sync byte, for baud rate measurement. Code will work for both types of silicon revisions if it waits for the end of the Break signal before setting ABDEN.

2. Module: Enhanced Capture/Compare/PWM (ECCP)

   In Section 15.5.9 “Setup for PWM Operation”, two words are changed in the first step of the procedure for setting up the ECCP module for Pulse-Width Modulation (PWM).

   The step now reads as shown, with bold text indicating the changes.

   1. Configure the PWM pins P1A and P1B (and P1C and P1D, if used) as outputs by clearing the corresponding TRISB bits.

   Note: Some silicon revisions use the falling edges of the Sync byte for baud rate measurement. In these devices, ABDEN may be set during the preceding Break. In other silicon revisions, the rising edges are used. In these devices, the RX input must be high (Break completed) before ABDEN is set. If this is not done, the end of the Break signal could be interpreted as the start of the Sync byte, for baud rate measurement. Code will work for both types of silicon revisions if it waits for the end of the Break signal before setting ABDEN.
REVISION HISTORY

First release of this errata. Clarification 1 (Enhanced
Addressable Universal Synchronous Asynchronous
Receiver Transmitter – EUSART).

Added clarification 2 (ECCP).
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